# <span id="page-0-0"></span>**BQ25713 / 713B I2C Narrow VDC Buck-Boost Battery Charge Controller With System Power Monitor and Processor Hot Monitor**

## **1 Features**

- Pin-to-pin and software compatible to BQ25703A
- Charge 1s to 4s battery from wide range of input source
	- 3.5-V to 24-V Input operating voltage
	- Supports USB2.0, USB 3.0, USB 3.1 (Type C), and USB Power Delivery (USB-PD) input current settings
	- Seamless transition among buck, buck-boost and boost operations
	- Input current and voltage regulation (IDPM and VDPM) against source overload
- Power/current monitor for CPU throttling
	- Comprehensive PROCHOT profile, IMVP8/ IMVP9 compliant
	- Input and battery current monitor
	- System power monitor, IMVP8/IMVP9 compliant
- Narrow voltage DC (NVDC) power path management
	- Instant-on with no battery or depleted battery
	- Battery supplements system when adapter is fully-loaded
	- Battery MOSFET ideal diode operation in supplement mode
- Power up USB port from battery (USB OTG)
	- 3-V to 20.8-V VOTG With 8-mV resolution
	- Output current limit up to 6.4 A with 50-mA resolution
- TI patented Pass Through Mode (PTM) for system power efficiency improvement and battery fast charging
- When system is powered by battery only, Vmin Active Protection (VAP) mode supplements battery from input capacitors during system peak power spike
- Input Current Optimizer (ICO) to extract max input power
- 800-kHz or 1.2-MHz Programmable switching frequency for 2.2-µH or 1.0-µH inductor
- Host control interface for flexible system configuration
	- $-$  I<sup>2</sup>C Port optimal system performance and status reporting
	- Hardware pin to set input current limit without EC control
- Integrated ADC to monitor voltage, current and power
- High accuracy for the regulation and monitor
	- ±0.5% Charge voltage regulation
	- ±2% Input/charge current regulation
	- ±2% Input/charge current monitor
	- ±4% Power monitor
- **Safety** 
	- Thermal shutdown
	- Input, system, battery overvoltage protection – Input, MOSFET, inductor overcurrent protection
	- Safety-Related Certifications:
	- IEC 62368-1 CB Certification
- Low battery quiescent current
- Package: 32-Pin 4 × 4 WQFN

## **2 Applications**

- Drones, Bluetooth speakers, IP cameras, detachable, tablet PCs and power bank
- Industrial and medical equipment
- Portable equipment with rechargeable batteries

## **3 Description**

This device is a synchronous NVDC buck-boost battery charge controller, offering a low component count, high efficiency solution for space constrained, 1s-4s battery charging applications.



(1) For all available packages, see the orderable addendum at the end of the data sheet.



**Application Diagram**

## **Table of Contents**





# **4 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.



#### **[BQ25713,](https://www.ti.com/product/BQ25713) [BQ25713B](https://www.ti.com/product/BQ25713B)**

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**Changes from Revision \* (June 2018) to Revision A (July 2018) Page**<br>
• Changed BQ25713 from Advance Information to Production Data and added BO25713B • Changed BQ25713 from Advance Information to Production Data and added BQ25713B .............................. [1](#page-0-0)

## <span id="page-3-0"></span>**5 Description (continued)**

The NVDC configuration allows the system to be regulated at battery voltage, but not drop below system minimum voltage. The system keeps operating even when the battery is completely discharged or removed. When load power exceeds input source rating, the battery goes into supplement mode and prevents the system from crashing.

BQ25713/BQ25713B charges battery from a wide range of input sources including USB adapter, high voltage USB PD sources and traditional adapters.

During power up, the charger sets converter to buck, boost or buck-boost configuration based on input source and battery conditions. The charger automatically transits among buck, boost and buck-boost configuration without host control.

In the absence of an input source, BQ25713/BQ25713B supports USB On-the-Go (OTG) function from 1- to 4 cell battery to generate adjustable 3 V to 20.8 V on VBUS with 8 mV resolution. The OTG output voltage transition slew rate can be configurable, which is complied with the USB PD 3.0 PPS specifications.

When only battery powers the system and no external load is connected to the USB OTG port, BQ25713/ BQ25713B supports the Vmin Active Protection (VAP) feature, in which the device charges up the VBUS voltage from the battery to store some energy in the input decoupling capacitors. During the system peak power spike, the huge current drawing from the battery creates a larger voltage drop across the impedance from the battery to the system. The energy stored in the input capacitors will supplement the system, to prevent the system voltage from dropping below the minimum system voltage and causing the system crash. This Vmin Active Protection (VAP) is designed to absorb system power peaks during periods of SOC high power demand, which is highly recommended by Intel for the platforms with 1S~2S battery.

BQ25713/BQ25713B monitors adapter current, battery current and system power. The flexibly programmed PROCHOT output goes directly to CPU for throttle back when needed.

## <span id="page-4-0"></span>**6 Device Comparison Table**



## <span id="page-5-0"></span>**7 Pin Configuration and Functions**









#### **Table 7-1. Pin Functions (continued)**







## <span id="page-8-0"></span>**8 Specifications**

## **8.1 Absolute Maximum Ratings**

over operating free-air temperature range (unless otherwise noted) $(1)$   $(2)$ 



(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to GND if not specified. Currents are positive into, negative out of the specified terminal. Consult Packaging Section of the data book for thermal limitations and considerations of packages.

#### **8.2 ESD Ratings**



(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

## **8.3 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)



#### <span id="page-9-0"></span>**8.3 Recommended Operating Conditions (continued)**

over operating free-air temperature range (unless otherwise noted)



#### **8.4 Thermal Information**



(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](http://www.ti.com/lit/SPRA953) application report.

#### **8.5 Electrical Characteristics**























<span id="page-17-0"></span>over T $_{\textrm{\scriptsize{J}}}$  = -40°C to 125°C (unless otherwise noted)



## **8.6 Timing Requirements**



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(1) Devices participating in a transfer will timeout when any clock low exceeds the 25ms minimum timeout period. Devices that have detected a timeout condition must reset the communication no later than the 35 ms maximum timeout period. Both a master and a slave must adhere to the maximum value specified as it incorporates the cumulative stretch limit for both a master (10 ms) and a slave (25 ms).

(2) User can adjust threshold via I2C ChargeOption() REG0x01/00().

## <span id="page-19-0"></span>**8.7 Typical Characteristics**





## **8.7 Typical Characteristics (continued)**

## <span id="page-21-0"></span>**9 Detailed Description**

#### **9.1 Overview**

The BQ25713/BQ25713B is a Narrow VDC buck-boost charger controller for portable electronics such as notebook, detachable, ultrabook, tablet and other mobile devices with rechargeable batteries. It provides seamless transition among different converter operation modes (buck, boost, or buck boost), fast transient response, and high light load efficiency.

BQ25713/BQ25713B supports wide range of power sources, including USB PD ports, legacy USB ports, traditional ACDC adapters, etc. It takes input voltage from 3.5 V to 24 V, and charges battery of 1-4 series. In the absence of an input source, BQ25713/BQ25713B supports USB On-the-Go (OTG) function from 1-4 cell battery to generate adjustable 3 V ~ 20.8 V at USB port with 8mV resolution. The OTG output voltage transition slew rate can be configurable, which complies with the USB Power Delivery 3.0 PPS specifications.

When only the battery powers the system and no external load is connected to the USB OTG port, BQ25713/ BQ25713B provides the Vmin Active Protection (VAP) feature. In the VAP operation, BQ25713/BQ25713B first charges up the voltage of the input decoupling capacitors at VBUS to store a certain amount of energy. During the system peak power spike, the huge current drawn from the battery introduces a larger voltage drop across the impedance from the battery to the system. Then the energy stored in the input capacitors will supplement the system, to prevent the system voltage from drooping below the minimum system voltage and leading the system to black screen. This VAP is designed to absorb system power peaks during the periods of high demand to improve the system turbo performance, which is highly recommended by Intel for the platforms with 1S~2S battery.

BQ25713/BQ25713B features Dynamic Power Management (DPM) to limit the input power and avoid AC adapter overloading. During battery charging, as the system power increases, the charging current will reduce to maintain total input current below adapter rating. If system power demand temporarily exceeds adapter rating, BQ25713/BQ25713B supports NVDC architecture to allow battery discharge energy to supplement system power. For details, refer to [Section 9.6.5.1](#page-57-0).

In order to be compliant with an Intel IMVP8 / IMVP9 compliant system, BQ25713/BQ25713B includes PSYS function to monitor the total platform power from adapter and battery. Besides PSYS, it provides both an independent input current buffer (IADPT) and a battery current buffer (IBAT) with highly accurate current sense amplifiers. If the platform power exceeds the available power from adapter and battery, a PROCHOT signal is asserted to CPU so that the CPU optimizes its performance to the power available to the system.

The I<sup>2</sup>C controls input current, charge current and charge voltage registers with high resolution, high accuracy regulation limits. It also sets the PROCHOT timing and threshold profile to meet system requirements.



#### <span id="page-22-0"></span>**9.2 Functional Block Diagram**

## <span id="page-23-0"></span>**9.3 Feature Description**

#### **9.3.1 Power-Up from Battery Without DC Source**

If only battery is present and the voltage is above  $V_{VBATUVLOZ}$ , the BATFET turns on and connects battery to system. By default, the charger is in low power mode (REG0x01[7] = 1) with lowest quiescent current. The LDO stays off. When device moves to performance mode (REG0x01[7] = 0), The host can enable IBAT buffer through <sup>12</sup>C to monitor discharge current. The PSYS, PROCHOT or independent comparator also can be enabled by the host through the  $I^2C$  commands. In performance mode, the REGN LDO is always available to provide an accurate reference for the other features.

#### **9.3.2 Vmin Active Protection (VAP) when Battery only Mode**

In VAP mode operation, the buck-boost charger delivers the energy from the battery to charge the voltage of the input decoupling capacitors (VBUS) as high as possible (like 20V). The system peak power pulse for a 2S1P or 1S2P system can be as high as 100W if the SoC and motherboard systems spikes coincide. These spikes are expected to be very rare, but possible. During these high power spikes, the charger is expected to supplement the battery (drawing the power from the charger's input decoupling capacitors) to prevent the system voltage from drooping. VAP allows the SoC to set much higher peak power levels to the SoC, thus provides for much better Turbo performance.

Follows the steps below to enter VAP operation.:

- 1. Set the voltage limit to charge VBUS in REG0x07/06().
- 2. Set the current limit to charge VBUS in REG0x09/08() and REG0x39[7:2].
- 3. Set the system voltage regulation point in REG0x0D[5:0], when the input cap supplements battery, the VSYS\_MIN regulation loop will maintain VSYS at this regulation point.
- 4. Set the PROCHOT VSYS TH1 threshold to trigger the VAP discharging VBUS in REG0x36[7:4].
- 5. Set the PROCHOT VSYS TH2 threshold to assert /PROCHOT active low signal to throttle SoC in REG0x36[3:2].
- 6. Enable the VAP mode by setting REG0x34[5] = 0, REG0x35[4] = 0, and pulling the OTG/VAP pin to high.

To exit VAP mode, the host should write either REG0x34[5] = 1 or pull low the OTG/VAP pin to low.

Any regular fault conditions of the charger in VAP mode will reset REG0x34[5] = 1, and the charger will exit VAP mode automatically.

#### **9.3.3 Power-Up From DC Source**

When an input source plugs in, the charger checks the input source voltage to turn on LDO and all the bias circuits. It sets the input current limit before the converter starts.

The power-up sequence from DC source is as follows:

- 1. 50 ms after VBUS above V<sub>VBUS CONVEN</sub>, enable 6 V LDO and CHRG\_OK goes HIGH
- 2. VBUS qualification is executed 50 ms after VBUS first rises above VVBUS\_UVLOZ. If

 $V_{VBUS\ UVLOZ}$  < VBUS <  $V_{VBUS\ CONVEN}$  then charger fails VBUS qualification, and the charger will re-qualify VBUS every 2s.

- 3. Input voltage and current limit setup
- 4. Battery CELL configuration
- 5. 150 ms after VBUS above  $V_{VBUS}$  converter powers up.

#### *9.3.3.1 CHRG\_OK Indicator*

CHRG\_OK is an active HIGH open drain indicator. It indicates the charger is in normal operation when the following conditions are valid:

- VBUS is above V<sub>VBUS\_CONVEN</sub>
- $\cdot$  VBUS is below V<sub>ACOV</sub>
- No MOSFET/inductor, or over-voltage, over-current, thermal shutdown fault

#### <span id="page-24-0"></span>*9.3.3.2 Input Voltage and Current Limit Setup*

After CHRG\_OK goes HIGH, the charger sets default input current limit in REG0x0F/0E() to 3.25 A. The actual input current limit being adopted by the device is the lower setting of REG0x0F/0E() and ILIM\_HIZ pin.

Charger initiates a VBUS voltage measurement without any load (VBUS at no load) right before the converter is enabled. The default VINDPM threshold is VBUS at no load – 1.28 V.

After input current and voltage limits are set, the charger device is ready to power up. The host can always program the input current and voltage limit after the charger being powered up, based on the input source type.

#### *9.3.3.3 Battery Cell Configuration*

CELL\_BATPRESZ pin is biased with a resistor divider from REGN to CELL\_BATPRESZ to GND. After VDDA LDO is activated, the device detects the battery configuration through CELL\_BATPRESZ pin bias voltage. Refer to Table 9-1 for cell setting thresholds.



#### **Table 9-1. Battery Cell Configuration**

#### *9.3.3.4 Device Hi-Z State*

The charger enters Hi-Z mode when ILIM\_HIZ pin voltage is below 0.4 V or REG0x35[7] is set to 1. During Hi-Z mode, the input source is present, and the charger is in the low quiescent current mode with REGN LDO enabled.

#### **9.3.4 USB On-The-Go (OTG)**

The device supports USB OTG operation to deliver power from the battery to other portable devices through USB port. The OTG mode output voltage is set in REG0x07/06(). The OTG mode output current is set in REG0x09/08(). The OTG operation can be enabled if the conditions are valid:

- Valid battery voltage is set REG0x05/04(), the battery voltage should not trip the BATOVP threshold, otherwise, the converter will stop switching.
- OTG output voltage is set in REG0x07/06() and REG0x34[2], if REG0x34[2] = 0, the VOTG digital DAC is offset by 1.28V to achieve higher range from 4.28V~20.8V, if REG0x34[2] = 1, the VOTG digital DAC is from 3V to 19.52V.
- OTG output current is set in REG0x09/08().
- EN OTG pin is HIGH, REG0x35[4] = 1 and REG0x34[5] = 1.
- VBUS is below V<sub>VBUS</sub> CONVENZ.
- 10 ms after the above conditions are valid, converter starts and VBUS ramps up to target voltage. CHRG\_OK pin goes HIGH if REG0x01[3] = 1.

#### **9.3.5 Converter Operation**

The charger employs a synchronous buck-boost converter that allows charging from a standard 5-V or a highvoltage power source. The charger operates in buck, buck-boost and boost mode. The buck-boost can operate uninterruptedly and continuously across the three operation modes.



#### **Table 9-2. MOSFET Operation**





#### *9.3.5.1 Inductance Detection through IADPT Pin*

The charger reads the inductance value through the resistance tied to IADPT pin before the converter starts up. The resistances recommended for 1uH, 2.2uH and 3.3uH inductance are 93kΩ, 137kΩ and 169kΩ, respectively. A surface mount chip resistor with ±3% or better tolerance must to be used for an accurate inductance detection.



#### **Table 9-3. Inductor Detection through IADPT Resistance**

#### *9.3.5.2 Continuous Conduction Mode (CCM)*

With sufficient charge or system current, the inductor current does not cross 0 A, which is defined as CCM. The controller starts a new cycle with ramp coming up from 200 mV. As long as the error amplifier output voltage is above the ramp voltage, the high-side MOSFET (HSFET) stays on. When the ramp voltage exceeds error amplifier output voltage, HSFET turns off and low-side MOSFET (LSFET) turns on. At the end of the cycle, ramp gets reset and LSFET turns off, ready for the next cycle. There is always break-before-make logic during transition to prevent cross-conduction and shoot-through. During the dead time when both MOSFETs are off, the body-diode of the low-side power MOSFET conducts the inductor current.

During CCM, the inductor current always flows and creates a fixed two-pole system. Having the LSFET turn-on when the HSFET is off keeps the power dissipation low and allows safe charging at high currents.

#### *9.3.5.3 Pulse Frequency Modulation (PFM)*

In order to improve converter light-load efficiency, BQ25713/BQ25713B switches to PFM operation at light load. The effective switching frequency will decrease accordingly when system load decreases. The minimum frequency can be limit to 25 kHz when the OOA feature is enabled (ChargeOption0() bit[10]=1).

#### **9.3.6 Current and Power Monitor**

#### *9.3.6.1 High-Accuracy Current Sense Amplifier (IADPT and IBAT)*

As an industry standard, a high-accuracy current sense amplifier (CSA) is used to monitor the charger input current during forward charging mode, or output current during OTG mode (IADPT) and the battery charge/ discharge current (IBAT). IADPT voltage is 20× or 40× the differential voltage across ACP and ACN. IBAT voltage is 8x/16× (during charging), or 8×/16× (during discharging) of the differential across SRP and SRN. After input voltage or battery voltage is above UVLO, IADPT output becomes valid. To lower the voltage on current monitoring, a resistor divider from CSA output to GND can be used and accuracy over temperature can still be achieved.

- $V_{(IADPT)}$  = 20 or 40 × (V<sub>(ACP)</sub> V<sub>(ACN)</sub>) during forward mode, or 20 or 40 × (V<sub>(ACN)</sub> V<sub>(ACP)</sub>) during reverse OTG mode.
- $V_{(IBAT)} = 8$  or 16 × (V<sub>(SRP)</sub> V<sub>(SRN)</sub>) for battery charging current.
- $V_{(IBAT)} = 8$  or 16 × (V<sub>(SRN)</sub> V<sub>(SRP)</sub>) for battery discharging current.

A maximum 100-pF capacitor is recommended to connect on the output for decoupling high-frequency noise. An additional RC filter is optional, if additional filtering is desired. Note that adding filtering also adds additional response delay. The CSA output voltage is clamped at 3.3 V.

## *9.3.6.2 High-Accuracy Power Sense Amplifier (PSYS)*

The charger monitors total system power. During forward mode, the input adapter powers system. During reverse OTG mode, the battery powers the system and VBUS output. The ratio of PSYS pin output current and total system power, K<sub>PSYS</sub>, can be programmed in REG0x31[1] with default 1  $\mu$ A/W. The input and charge sense

resistors (RAC and RSR) are selected in REG0x31[3:2]. PSYS voltage can be calculated with Equation 1, where  $I_{\text{IN}}$ >0 I<sub>BAT</sub> <0 when the charger is in forward charging with an adapter connected, and I<sub>BAT</sub> >0 when the battery is in discharging mode.

$$
V_{PSYS} \quad R_{PSYS} \times K_{PSYS} (V_{ACP} \times I_{IN} + V_{BAT} \times I_{BAT}) \tag{1}
$$

For proper PSYS functionality, RAC and RSR values are limited to 10 mΩ and 20 mΩ.

To minimize the quiescent current, the PSYS function is disabled by default. It can be enabled by setting  $REG0x31[4] = 1.$ 

#### **9.3.7 Input Source Dynamic Power Manage**

Refer to [Section 9.6.6](#page-58-0).

#### **9.3.8 Two-Level Adapter Current Limit (Peak Power Mode)**

Usually adapter can supply current higher than DC rating for a few milliseconds to tens of milliseconds. The charger employs two-level input current limit, or peak power mode, to fully utilize the overloading capability and minimize battery discharge during CPU turbo mode. Peak power mode is enabled in REG0x33[5:4]. The DC current limit, or  $I_{LIM1}$ , is the same as adapter DC current, set in REG0x0F/0E(). The overloading current, or  $I_{LIM2}$ , is set in REG0x37[7:3], as a percentage of  $I_{LIM1}$ .

When the charger detects input current surge and battery discharge due to load transient (both the adapter and battery support the system together), or when the charger detects the system voltage starts to drop due to load transient (only the adapter supports the system), the charger will first apply  $I_{LIM2}$  for  $T_{OVLD}$  in REG0x33[7:6], and then  $I_{LIM1}$  for up to  $T_{MAX} - T_{OVLD}$  time.  $T_{MAX}$  is programmed in REG0x33[1:0]. After  $T_{MAX}$  if the load is still high, another peak power cycle starts. Charging is disabled during  $T_{MAX}$ ; once  $T_{MAX}$ , expires, charging continues. If  $T_{\mathsf{OVLD}}$  is programmed to be equal to  $T_{\mathsf{MAX}}$ , then peak power mode is always on.



**Figure 9-1. Two-Level Adapter Current Limit Timing Diagram**

#### **9.3.9 Processor Hot Indication**

When CPU is running turbo mode, the system peak power may exceed available power from adapter and battery together. The adapter current and battery discharge peak current, or system voltage drop is an indication that system power is too high. The charger processor hot function monitors these events, and PROCHOT pulse is asserted if the system power is too high. Once CPU receives PROCHOT pulse from charger, it slows down to reduce system power. The events monitored by the processor hot function includes:

- ICRIT: adapter peak current, as 110% of  $I_{LIM2}$
- INOM: adapter average current (110% of input current limit)
- IDCHG: battery discharge current
- VSYS: system voltage on VSYS
- Adapter Removal: upon adapter removal (CHRG\_OK pin HIGH to LOW)
- Battery Removal: upon battery removal (CELL\_BATPRESZ pin goes LOW)
- CMPOUT: Independent comparator output (CMPOUT pin HIGH to LOW)
- VDPM: VBUS lower than 80%/90%/100% of VINDPM threshold.
- EXIT\_VAP: Every time when the charger exits VAP mode.

The threshold of ICRIT, IDCHG, VSYS or VDPM, and the deglitch time of ICRIT, INOM, IDCHG or CMPOUT are programmable through I<sup>2</sup>C. Except the PROCHOT\_EXIT\_VAP is always enabled, the other triggering events can be individually enabled in REG0x38[7:0]. When any enabled event in PROCHOT profile is triggered, PROCHOT is asserted low for a single pulse with minimal width programmable in REG0x23[5:4]. At the end of the single pulse, if the PROCHOT event is still active, the pulse gets extended until the event is removed.

If the PROCHOT pulse extension mode is enabled by setting REG0x23[6] = 1, the PROCHOT pin will be kept as low until host writes REG0x23[3]21[11] = 0, even if the triggering event has been removed.

If the PROCHOT\_VDPM or PROCHOT\_EXIT\_VAP is triggered, PROCHOT pin will always stay low until the host clears it, no matter the PROCHOT is in one pulse mod or in extended mode.

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**Figure 9-2. PROCHOT Profile**

#### *9.3.9.1 PROCHOT During Low Power Mode*

During low power mode (REG0x01[7] = 1), the charger offers a low power  $\overline{PROCHOT}$  function with very low quiescent current consumption (~150uA), which uses the independent comparator to monitor the system voltage, and assert PROCHOT to CPU if the system power is too high.

Below lists the register setting to enable PROCHOT monitoring system voltage in low power mode.

- REG0x01[7] = 1 to enable charger low power mode.
- REG0x38[7:0] = 00h
- REG0x30[6:4] = 100
- Independent comparator threshold is always 1.2 V
- When REG0x31[5] = 1, charger monitors system voltage. Connect CMPIN to voltage proportional to system. PROCHOT triggers from HIGH to LOW when CMPIN voltage rises above 1.2 V.



**Figure 9-3. PROCHOT Low Power Mode Implementation**

## *9.3.9.2 PROCHOT Status*

REG0x22[7:0] and REG0x23[0] reports which event in the profile triggers PROCHOT if the corresponding bit is set to 1. The status bit can be reset back to 0 after it is read by host, when the current PROCHOT event is not active any more.

Assume there are two PROCHOT events, event A and event B. Event A triggers PROCHOT first, but event B is also active. Both status bits will be HIGH. At the end of the 10 ms PROCHOT pulse, if any of the PROCHOT event is still active (either A or B), the PROCHOT pulse is extended.

## **9.3.10 Device Protection**

## *9.3.10.1 Watchdog Timer*

The charger includes watchdog timer to terminate charging if the charger does not receive a write MaxChargeVoltage() or write ChargeCurrent() command within 175 s (adjustable via REG0x01[6:5]). When watchdog timeout occurs, all register values are kept unchanged except ChargeCurrent() resets to zero. Battery charging is suspended. Write MaxChargeVoltage() or write ChargeCurrent() commands must be re-sent to reset watchdog timer and resume charging. Writing REG0x01[6:5] = 00 to disable watchdog timer also resumes charging.

## *9.3.10.2 Input Overvoltage Protection (ACOV)*

The charger has fixed ACOV voltage. When VBUS pin voltage is higher than ACOV, it is considered as adapter over voltage. CHRG\_OK will be pulled low, and converter will be disabled. As system falls below battery voltage, BATFET will be turned on. When VBUS pin voltage falls below ACOV, it is considered as adapter voltage returns back to normal voltage. CHRG\_OK is pulled high by external pull up resistor. The converter resumes if enable conditions are valid.

## *9.3.10.3 Input Overcurrent Protection (ACOC)*

If the input current exceeds the 1.33× or 2× (REG0x32[2]) of  $I_{LIM2VTH}$  (REG0x37[7:3]) set point, converter stops switching. After 300 ms, converter starts switching again.

## *9.3.10.4 System Overvoltage Protection (SYSOVP)*

When the converter starts up, BQ25713/BQ25713B reads CELL pin configuration and sets MaxChargeVoltage() and SYSOVP threshold (1s – 5 V, 2s – 12 V, 3s/4s – 19.5 V). Before REGx05/04() is written by the host, the <span id="page-30-0"></span>battery configuration will change with CELL pin voltage. When SYSOVP happens, the device latches off the converter. REG0x20[4] is set to 1. The user can clear latch-off by either writing 0 to the SYSOVP bit or removing and plugging in the adapter again. After latch-off is cleared, the converter starts again.

#### *9.3.10.5 Battery Overvoltage Protection (BATOVP)*

Battery over-voltage may happen when battery is removed during charging or the user plugs in a wrong battery. The BATOVP threshold is 104% (1 s) or 102% (2 s to 4 s) of regulation voltage set in REG0x05/04().

#### *9.3.10.6 Battery Short*

If BAT voltage falls below SYSMIN during charging, the maximum current is limited to 384 mA.

#### *9.3.10.7 System Short Hiccup Mode*

VSYS pin is monitoring the system voltage, when Vsys is lower than 2.4V, after 2ms deglitch time, the charger will be shut down for 500ms. The charger will restart for 10ms and measure Vsys again, if it is still lower than 2.4V, the charger will be shut down again. This hiccup mode will be tried continuously, if the charger restart is failed for 7 times in 90 second, the charger will be latched off. REG0x20[3] will be set to 1 to report a system short fault. The charger only can be enabled again once the host writes REG0x20[3]= 0.

The charger system short hiccup mode can be disabled by writing REG0x00[6]= 1.

#### *9.3.10.8 Thermal Shutdown (TSHUT)*

The WQFN package has low thermal impedance, which provides good thermal conduction from the silicon to the ambient, to keep junction temperatures low. As added level of protection, the charger converter turns off for selfprotection whenever the junction temperature exceeds the 155°C. The charger stays off until the junction temperature falls below 135°C. During thermal shut down, the LDO current limit is reduced to 16 mA and REGN LDO stays off. When the temperature falls below 135°C, charge can be resumed with soft start.

## **9.4 Device Functional Modes**

#### **9.4.1 Forward Mode**

When input source is connected to VBUS, BQ25713/BQ25713B is in forward mode to regulate system and charge battery.

#### *9.4.1.1 System Voltage Regulation with Narrow VDC Architecture*

BQ25713/BQ25713B employs Narrow VDC architecture (NVDC) with BATFET separating system from battery. The minimum system voltage is set by MinSystemVoltage(). Even with a deeply depleted battery, the system is regulated above the minimum system voltage.

When the battery is below minimum system voltage setting, the BATFET operates in linear mode (LDO mode).

As the battery voltage rises above the minimum system voltage, BATFET is fully on when charging or in supplement mode and the voltage difference between the system and battery is the VDS of BATFET. System voltage is regulated 160 mV above battery voltage when BATFET is off (no charging or no supplement current).

The BATDRV pin is only able to drive a battery MOSFET with Ciss lower than 5nF. The Ciss in the range of 1nF~3nF is recommended.

See [Section 9.6.5.1](#page-57-0) for details on system voltage regulation and register programming.

#### *9.4.1.2 Battery Charging*

BQ25713/BQ25713B charges 1-4 cell battery in constant current (CC), and constant voltage (CV) mode. Based on CELL\_BATPREZ pin setting, the charger sets default battery voltage 4.2V/cell to ChargeVoltage(), or REG0x05/04(). According to battery capacity, the host programs appropriate charge current to ChargeCurrent(), or REG0x03/02(). When battery is full or battery is not in good condition to charge, host terminates charge by setting REG0x00[0] to 1, or setting ChargeCurrent() to zero.

See [Section 9.3](#page-23-0) for details on register programming.

#### <span id="page-31-0"></span>**9.4.2 USB On-The-Go**

BQ25713/BQ25713B supports USB OTG functionality to deliver power from the battery to other portable devices through USB port (reverse mode). The OTG output voltage is compliant with USB PD specification, including 5 V, 9 V, 15 V, and 20 V. The output current regulation is compliant with USB type C specification, including 500 mA, 1.5 A, 3 A and 5 A.

Similar to forward operation, the device switches from PWM operation to PFM operation at light load to improve efficiency.

#### **9.4.3 Pass Through Mode (PTM)**

When the system is in the sleep mode or light load condition, the charger can be operated in the pass through mode to improve the light load efficiency. In TI patented pass through mode (PTM), the Buck and Boost high side FETs are both turned on, while the Buck and Boost low side FETs are both turned off. The input power is directly passed through the charger to the system. The switching losses of MOSFETs and the inductor core loss are saved.

Device will be transition from normal Buck-Boost operation to PTM operation by:

- Set REG0x32[7] = 0, to disable the EN\_EXITILIM.
- Set REG0x31[0] = 1.
- Set REG0x30[2] = 1.
- Ground ILIM HIZ pin.

Device will transition out of PTM mode with host control by:

- $Set REGOx30[2] = 0.$
- Pull ILIM HIZ pin to high.
- Device exits PTM to buck-boost operation if tripping VINDPM.
- Device exits PTM to buck-boost operation under fault conditions

#### **9.5 Programming**

The charger supports battery-charger commands that use either Write-Word or Read-Word protocols, as summarized in Section 9.5.1. The I2C address is D6h. The ManufacturerID and DeviceID registers are assigned identify the charger device. The ManufacturerID register command always returns 40h.

#### **9.5.1 I2C Serial Interface**

The BQ25713/BQ25713B uses I<sup>2</sup>C compatible interface for flexible charging parameter programming and instantaneous device status reporting. I<sup>2</sup>C is a bi-directional 2-wire serial interface. Only two bus lines are required: a serial data line (SDA) and a serial clock line (SCL). Devices can be considered as masters or slaves when performing data transfers. A master is the device which initiates a data transfer on the bus and generates the clock signals to permit that transfer. At that time, any device addressed is considered a slave.

The device operates as a slave device with address D6h, receiving control inputs from the master device like micro controller or a digital signal processor through REG00-REG3A. The I<sup>2</sup>C interface supports both standard mode (up to 100 kbits), and fast mode (up to 400 kbits). connecting to the positive supply voltage via a current source or pull-up resistor. When the bus is free, both lines are HIGH. The SDA and SCL pins are open drain.

#### *9.5.1.1 Data Validity*

The data on the SDA line must be stable during the HIGH period of the clock. The HIGH or LOW state of the data line can only change when the clock signal on the SCL line is LOW. One clock pulse is generated for each data bit transferred.



**Figure 9-4. Bit Transfer on the I2C Bus**

#### *9.5.1.2 START and STOP Conditions*

All transactions begin with a START (S) and can be terminated by a STOP (P). A HIGH to LOW transition on the SDA line while SCL is HIGH defines a START condition. A LOW to HIGH transition on the SDA line when the SCL is HIGH defines a STOP condition.

START and STOP conditions are always generated by the master. The bus is considered busy after the START condition, and free after the STOP condition.



**Figure 9-5. START and STOP Conditions**

#### *9.5.1.3 Byte Format*

Every byte on the SDA line must be 8 bits long. The number of bytes to be transmitted per transfer is unrestricted. Each byte has to be followed by an Acknowledge bit. Data is transferred with the Most Significant Bit (MSB) first. If a slave cannot receive or transmit another complete byte of data until it has performed some other function, it can hold the clock line SCL low to force the master into a wait state (clock stretching). Data transfer then continues when the slave is ready for another byte of data and release the clock line SCL.



**Figure 9-6. Data Transfer on the I2C Bus**

#### *9.5.1.4 Acknowledge (ACK) and Not Acknowledge (NACK)*

The acknowledge takes place after every byte. The acknowledge bit allows the receiver to signal the transmitter that the byte was successfully received and another byte may be sent. All clock pulses, including the acknowledge 9th clock pulse, are generated by the master.

The transmitter releases the SDA line during the acknowledge clock pulse so the receiver can pull the SDA line LOW and it remains stable LOW during the HIGH period of this clock pulse.

When SDA remains HIGH during the 9th clock pulse, this is the Not Acknowledge signal. The master can then generate either a STOP to abort the transfer or a repeated START to start a new transfer.

#### *9.5.1.5 Slave Address and Data Direction Bit*

After the START, a slave address is sent. This address is 7 bits long followed by the eighth bit as a data direction bit (bit R/W). A zero indicates a transmission (WRITE) and a one indicates a request for data (READ).



**Figure 9-7. Complete Data Transfer**

## *9.5.1.6 Single Read and Write*



## **Figure 9-8. Single Write**



**Figure 9-9. Single Read**

If the register address is not defined, the charger IC send back NACK and go back to the idle state.

## *9.5.1.7 Multi-Read and Multi-Write*

The charger device supports multi-read and multi-write.



**Figure 9-10. Multi Write**

<span id="page-34-0"></span>

#### **Figure 9-11. Multi Read**

#### *9.5.1.8 Write 2-Byte I2C Commands*

A few I2C commands combine two 8-bit registers together to form a complete value. These commands include:

- ChargeCurrent()
- MaxChargeVoltage()
- IIN DPM()
- OTGVoltage()
- InputVoltage()

Host has to write LSB command followed by MSB command. No other command can be inserted in between these two writes. The charger waits for the complete write to the two registers to decide whether to accept or ignore the new value.

After the completion of LSB and MSB bytes, the two bytes will be updated at the same time. If host writes MSB byte first, the command will be ignored. If the time between write of LSB and MSB bytes exceeds watchdog timer, both the LSB and MSB commands will be ignored.



#### **Table 9-4. Charger Command Summary**



#### **[BQ25713,](https://www.ti.com/product/BQ25713) [BQ25713B](https://www.ti.com/product/BQ25713B)** SLUSD83B – JUNE 2018 – REVISED FEBRUARY 2021



#### **Table 9-4. Charger Command Summary (continued)**
# **9.6.1 Setting Charge and PROCHOT Options**

# *9.6.1.1 ChargeOption0 Register (I2C address = 01/00h) [reset = E70Eh]*

# **Figure 9-12. ChargeOption0 Register (I2C address = 01/00h) [reset = E70Eh]**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

## **Table 9-5. ChargeOption0 Register (I2C address = 01h) Field Descriptions**







# **Table 9-6. ChargeOption0 Register (I2C address = 00h) Field Descriptions**





## *9.6.1.2 ChargeOption1 Register (I2C address = 31/30h) [reset = 0211h]*

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 9-7. ChargeOption1 Register (I2C address = 31h) Field Descriptions**



## **Table 9-8. ChargeOption1 Register (I2C address = 30h) Field Descriptions**



# **Table 9-8. ChargeOption1 Register (I2C address = 30h) Field Descriptions (continued)**







# **Figure 9-14. ChargeOption2 Register (I2C address = 33/32h) [reset = 02B7h]**

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 9-9. ChargeOption2 Register (I2C address = 33h) Field Descriptions**



## **Table 9-10. ChargeOption2 Register (I2C address = 32h) Field Descriptions**



# **Table 9-10. ChargeOption2 Register (I2C address = 32h) Field Descriptions (continued)**





# *9.6.1.4 ChargeOption3 Register (I2C address = 35/34h) [reset = 0030h]*

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

## **Table 9-11. ChargeOption3 Register (I2C address = 35h) Field Descriptions**



## **Table 9-12. ChargeOption3 Register (I2C address = 34h) Field Descriptions**







# *9.6.1.5 ProchotOption0 Register (I2C address = 37/36h) [reset = 04A65h]*



### **Figure 9-16. ProchotOption0 Register (I2C address = 37/36h) [reset = 04A65h]**

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

## **Table 9-13. ProchotOption0 Register (I2C address = 37h) Field Descriptions**



# **Table 9-14. ProchotOption0 Register (I2C address = 36h) Field Descriptions**





# **Table 9-14. ProchotOption0 Register (I2C address = 36h) Field Descriptions (continued)**

## *9.6.1.6 ProchotOption1 Register (I2C address = 39/38h) [reset = 81A0h]*



### **Figure 9-17. ProchotOption1 Register (I2C address = 39/38h) [reset = 81A0h]**

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

When the REG0x38[7:0] are set to be disabled, the PROCHOT event associated with that bit will not be reported in the PROCHOT status register REG0x22[7:0] any more, and the PROCHOT pin will not be pulled low any more if the event happens.

**Table 9-15. ProchotOption1 Register (I2C address = 39h) Field Descriptions**

$1^2C$ 39h	<b>FIELD</b>	<b>TYPE</b>	<b>RESET</b>	<b>IDESCRIPTION</b>
$7-2$	<b>IDCHG VTH</b>	R/W	100000b	<b>IDCHG Threshold</b> 6 bit, range, range 0 A to 32256 mA, step 512 mA. There is a 128 mA offset. Measure current between SRN and SRP. Trigger when the discharge current is above the threshold. If the value is programmed to 000000b, PROCHOT is always triggered. Default: 16384 mA or 100000b
$1 - 0$	<b>IDCHG DEG</b>	R/W	01b	<b>IDCHG Deglitch Time</b> 00 $b: 1.6$ ms 01b: 100 µs <default at="" por=""> <math>10b</math>: 6 ms 11<math>b: 12</math> ms</default>



## **Table 9-16. ProchotOption1 Register (I2C address = 38h) Field Descriptions**



# **Table 9-16. ProchotOption1 Register (I2C address = 38h) Field Descriptions (continued)**

## *9.6.1.7 ADCOption Register (I2C address = 3B/3Ah) [reset = 2000h]*



#### **Figure 9-18. ADCOption Register (I2C address = 3B/3Ah) [reset = 2000h]**

LEGEND:  $R/W = Read/Write$ ;  $R = Read$  only; -n = value after reset

The ADC registers are read in the following order: VBAT, VSYS, ICHG, IDCHG, IIN, PSYS, VBUS, CMPIN. ADC is disabled in low power mode. When enabling ADC, the device exit low power mode at battery only.



## **Table 9-17. ADCOption Register (I2C address = 3Bh) Field Descriptions**

## **Table 9-18. ADCOption Register (I2C address = 3Ah) Field Descriptions**



## **9.6.2 Charge and PROCHOT Status**

#### *9.6.2.1 ChargerStatus Register (I <sup>2</sup>C address = 21/20h) [reset = 0000h]*

## **Figure 9-19. ChargerStatus Register (I2C address = 21/20h) [reset = 0000h]**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 9-19. ChargerStatus Register (I2C address = 21h) Field Descriptions**



#### **Table 9-20. ChargerStatus Register (I2C address = 20h) Field Descriptions**



# **Table 9-20. ChargerStatus Register (I2C address = 20h) Field Descriptions (continued)**





# *9.6.2.2 ProchotStatus Register (I2C address = 23/22h) [reset = A800h]*

**Figure 9-20. ProchotStatus Register (I2C address = 23/22h) [reset = A800h]**

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 9-21. ProchotStatus Register (I2C address = 23h) Field Descriptions**



### **Table 9-22. ProchotStatus Register (I2C address = 22h) Field Descriptions**





# **Table 9-22. ProchotStatus Register (I2C address = 22h) Field Descriptions (continued)**

### **9.6.3 ChargeCurrent Register (I2C address = 03/02h) [reset = 0000h]**

To set the charge current, write a 16-bit ChargeCurrent() command (REG0x03/02h()) using the data format listed in Figure 9-21, Table 9-23, and Table 9-24.

With 10-mΩ sense resistor, the charger provides charge current range of 64 mA to 8.128 A, with a 64-mA step resolution. Upon POR, when auto wakeup is not active, ChargeCurrent() is 0 A. Any conditions for CHRG\_OK low except ACOV will reset ChargeCurrent() to zero. CELL\_BATPRESZ going LOW (battery removal) will reset the ChargeCurrent() register to 0 A.

Charge current is not reset in ACOC, TSHUT, power path latch off (REG0x30[1]), and SYSOVP.

A 0.1-µF capacitor between SRP and SRN for differential mode filtering is recommended; an optional 0.1-µF capacitor between SRN and ground, and an optional 0.1-µF capacitor between SRP and ground for common mode filtering. Meanwhile, the capacitance on SRP should not be higher than 0.1 µF in order to properly sense the voltage across SRP and SRN for cycle-by-cycle current detection.

The SRP and SRN pins are used to sense voltage drop across RSR with default value of 10 mΩ. However, resistors of other values can also be used. For a larger sense resistor, a larger sense voltage is given, and a higher regulation accuracy; but, at the expense of higher conduction loss. A current sensing resistor value no more than 20 mΩ is suggested.

### **Figure 9-21. ChargeCurrent Register With 10-mΩ Sense Resistor (I2C address = 03/02h) [reset = 0h]**



LEGEND:  $R/W = Read/Write$ ;  $R = Read$  only; -n = value after reset

#### **Table 9-23. Charge Current Register (14h) With 10-mΩ Sense Resistor (I2C address = 03h) Field Descriptions**



### **Table 9-24. Charge Current Register (14h) With 10-mΩ Sense Resistor (I2C address = 02h) Field Descriptions**



### **Table 9-24. Charge Current Register (14h) With 10-mΩ Sense Resistor (I2C address = 02h) Field Descriptions (continued)**



### *9.6.3.1 Battery Pre-Charge Current Clamp*

During pre-charge, BATFET works in linear mode or LDO mode (default REG0x00[2] = 1). For 2-4 cell battery, the system is regulated at minimum system voltage in REG0x0D/0C() and the pre-charge current is clamped at 384 mA. For 1 cell battery, the pre-charge to fast charge threshold is 3 V, and the pre-charge current is clamped at 384 mA. However, the BATFET stays in LDO mode operation till battery voltage is above minimum system voltage (~3.6 V). During battery voltage from 3 V to 3.6 V, the fast charge current is clamped at 2 A.

### **9.6.4 MaxChargeVoltage Register (I2C address = 05/04h) [reset value based on CELL\_BATPRESZ pin setting]**

To set the output charge voltage, write a 16-bit ChargeVoltage register command (REG0x05/04()) using the data format listed in Figure 9-22, Table 9-25, and Table 9-26. The charger provides charge voltage range from 1.024 V to 19.200 V, with 8-mV step resolution. Any write below 1.024 V or above 19.200 V is ignored.

Upon POR, REG0x05/04() is by default set as 4200 mV for 1 s, 8400 mV for 2 s, 12600 mV for 3 s or 16800 mV for 4 s. After CHRG\_OK goes high, the charge will start when the host writes the charging current to REG0x03/02(), the default charging voltage is used if REG0x05/04() is not programmed. If the battery is different from 4.2 V/cell, the host has to write to REG0x05/04() before REG0x03/02() for correct battery voltage setting. Writing REG0x05/04() to 0 will set REG0x05/04() to the default value based on CELL\_BATPRESZ pin, and force REG0x03/02() to zero to disable charge.

The SRN pin senses the battery voltage for voltage regulation and should be connected as close to the battery as possible, and directly place a decoupling capacitor (0.1 µF recommended) as close to the device as possible to decouple high frequency noise.

#### **Figure 9-22. MaxChargeVoltage Register (I2C address = 05/04h) [reset value based on CELL\_BATPRESZ pin setting]**



LEGEND:  $R/W = Read/W$ rite;  $R = Read$  only; -n = value after reset

#### **Table 9-25. MaxChargeVoltage Register (I2C address = 05h) Field Descriptions**



## **Table 9-26. MaxChargeVoltage Register (I2C address = 04h) Field Descriptions**







### **9.6.5 MinSystemVoltage Register (I2C address = 0D/0Ch) [reset value based on CELL\_BATPRESZ pin setting]**

To set the minimum system voltage, write a 16-bit MinSystemVoltage register command (REG0x0D/0C()) using the data format listed in Figure 9-23, Table 9-27, and Table 9-28. The charger provides minimum system voltage range from 1.024 V to 16.128 V, with 256-mV step resolution. Any write below 1.024 V or above 16.128 V is ignored. Upon POR, the MinSystemVoltage register is 3.584 V for 1 S, 6.144 V for 2 S and 9.216 V for 3 S, and 12.288 V for 4 S.

#### **Figure 9-23. MinSystemVoltage Register (I2C address = 0D/0Ch) [reset value based on CELL\_BATPRESZ pin setting]**



LEGEND:  $R/W = Read/Write$ ;  $R = Read$  only; -n = value after reset

#### **Table 9-27. MinSystemVoltage Register (I2C address = 0Dh) Field Descriptions**



## **Table 9-28. MinSystemVoltage Register (I2C address = 0Ch) Field Descriptions**



### *9.6.5.1 System Voltage Regulation*

The device employs Narrow VDC architecture (NVDC) with BATFET separating system from battery. The minimum system voltage is set by REG0x0D/0C(). Even with a deeply depleted battery, the system is regulated above the minimum system voltage with BATFET.

When the battery is below minimum system voltage setting, the BATFET operates in linear mode (LDO mode), and the system is regulated above the minimum system voltage setting. As the battery voltage rises above the minimum system voltage, BATFET is fully on when charging or in supplement mode and the voltage difference between the system and battery is the VDS of BATFET. System voltage is regulated 160 mV above battery voltage when BATFET is off (no charging or no supplement current).

When BATFET is removed, the system node VSYS is shorted to SRP. Before the converter starts operation, LDO mode needs to be disabled. The following sequence is required to configure charger without BATFET.

- 1. Before adapter plugs in, put the charger into HIZ mode. (either pull pin 6 ILIM\_HIZ to ground, or set REG0x35[7] to 1)
- 2. Set 0x00[2] to 0 to disable LDO mode.
- 3. Set 0x30[0] to 0 to disable auto-wakeup mode.
- 4. Check if battery voltage is properly programmed (REG0x05/04)
- 5. Set pre-charge/charge current (REG0x03/02)
- 6. Put the device out of HIZ mode. (Release ILIM\_HIZ from ground and set REG0x35[7]=0).

In order to prevent any accidental SW mistakes, the host sets low input current limit (a few hundred milliamps) when device is out of HIZ.

### **9.6.6 Input Current and Input Voltage Registers for Dynamic Power Management**

The charger supports Dynamic Power Management (DPM). Normally, the input power source provides power for the system load or to charge the battery. When the input current exceeds the input current setting, or the input voltage falls below the input voltage setting, the charger decreases the charge current to provide priority to the system load. As the system current rises, the available charge current drops accordingly towards zero. If the system load keeps increasing after the charge current drops down to zero, the system voltage starts to drop. As the system voltage drops below the battery voltage, the battery will discharge to supply the heavy system load.

### *9.6.6.1 Input Current Registers*

To set the maximum input current limit, write a 16-bit IIN HOST register command (REG0x0F/0E()) using the data format listed in [Table 9-29](#page-59-0) and [Table 9-30](#page-59-0). When using a 10-mΩ sense resistor, the charger provides an input-current limit range of 50 mA to 6400 mA, with 50-mA resolution. The default current limit is 3.25 A. Due to the USB current setting requirement, the register setting specifies the maximum current instead of the typical current. Upon adapter removal, the input current limit is reset to the default value of 3.25 A. With code 0, the input current limit is 50 mA.

The ACP and ACN pins are used to sense R<sub>AC</sub> with the default value of 10 mΩ. For a 20-mΩ sense resistor, a larger sense voltage is given and a higher regulation accuracy, but at the expense of higher conduction loss.

Instead of using the internal DPM loop, the user can build up an external input current regulation loop and have the feedback signal on the ILIM\_HIZ pin.

$$
V_{\text{ILIM\_HIZ}} = 1V + 40 \times (V_{\text{ACP}} - V_{\text{ACN}}) = 1 + 40 \times I_{\text{DPM}} \times R_{\text{AC}}
$$
\n(2)

In order to disable ILIM HIZ pin, the host can write to 0x32[7] to disable ILIM HIZ pin, or pull ILIM HIZ pin above 4.0 V.

#### <span id="page-59-0"></span>**9.6.6.1.1 IIN\_HOST Register With 10-mΩ Sense Resistor (I2C address = 0F/0Eh) [reset = 4100h]**

With code 0, the input current limit readback is 50 mA.

#### **Figure 9-24. IIN\_HOST Register With 10-mΩ Sense Resistor (I2C address = 0F/0Eh) [reset = 4100h]**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 9-29. IIN\_HOST Register With 10-mΩ Sense Resistor (I2C address = 0Fh) Field Descriptions**



#### **Table 9-30. IIN\_HOST Register With 10-mΩ Sense Resistor (I2C address = 0Eh) Field Descriptions**



#### **9.6.6.1.2 IIN\_DPM Register With 10-mΩ Sense Resistor (I2C address = 25/24h) [reset = 4100h]**

IIN\_DPM register reflects the actual input current limit programmed in the register, either from host or from ICO.

After ICO, the current limit used by DPM regulation may differ from the IIN\_HOST register settings. The actual DPM limit is reported in REG0x25/24(). With code 0, the input current limit read-back is 50 mA.

#### **Figure 9-25. IIN\_DPM Register With 10-mΩ Sense Resistor (I2C address = 25/24h) [reset = 4100h]**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

### **Table 9-31. IIN\_DPM Register With 10-mΩ Sense Resistor (I2C address = 25h) Field Descriptions**



### **Table 9-32. IIN\_DPM Register With 10-mΩ Sense Resistor (I2C address = 24h) Field Descriptions**



#### **9.6.6.1.3 InputVoltage Register (I2C address = 0B/0Ah) [reset = VBUS-1.28V]**

To set the input voltage limit, write a 16-bit InputVoltage register command (REG0x0B/0A()) using the data format listed in Figure 9-26, Table 9-33, and Table 9-34.

If the input voltage drops more than the InputVoltage register allows, the device enters DPM and reduces the charge current. The default offset voltage is 1.28 V below the no-load VBUS voltage. The DC offset is 3.2 V  $(0000000)$ .

**Figure 9-26. InputVoltage Register (I2C address = 0B/0Ah) [reset = VBUS-1.28V]**

6		5	4	3			0			
	Reserved	Input Voltage, bit 7	Input Voltage, bit 6	Input Voltage, bit 5	Input Voltage, bit 4	Input Voltage, bit 3	Input Voltage, bit 2			
	R/W									
	6	5	4	3			0			
Input Voltage, bit 1	Input Voltage, bit 0	Reserved								
R/W	R/W	R/W								

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 9-33. InputVoltage Register (I2C address = 0Bh) Field Descriptions**



#### **Table 9-34. InputVoltage Register (I2C address = 0Ah) Field Descriptions**



#### **9.6.7 OTGVoltage Register (I2C address = 07/06h) [reset = 0000h]**

To set the OTG output voltage limit, write to REG0x07/06() using the data format listed in Figure 9-27, Table 9-35, and Table 9-36.

The DAC is clamped in digital core at minimal 3V and maximum 20.8V. Any register writing lower than the minimal or higher than the maximum will be ignored. When REG0x34[2] = 1, there is no DAC offset. When REG0x34[2] = 0 the DAC is offset by 1.28V



# **Figure 9-27. OTGVoltage Register (I2C address = 07/06h) [reset = 0000h]**

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

### **Table 9-35. OTGVoltage Register (I2C address = 07h) Field Descriptions**



#### **Table 9-36. OTGVoltage Register (I2C address = 06h) Field Descriptions**



### **9.6.8 OTGCurrent Register (I2C address = 09/08h) [reset = 0000h]**

To set the OTG output current limit, write to REG0x09/08() using the data format listed in Figure 9-28, Table 9-37, and Table 9-38.





LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

## **Table 9-37. OTGCurrent Register (I2C address = 09h) Field Descriptions**



# **Table 9-38. OTGCurrent Register (I2C address = 08h) Field Descriptions**



# **9.6.9 ADCVBUS/PSYS Register (I2C address = 27/26h)**

- PSYS: Full range: 3.06 V, LSB: 12 mV
- VBUS: Full range: 3200 mV to 19520 mV, LSB: 64 mV

## **Figure 9-29. ADCVBUS/PSYS Register (I2C address = 27/26h)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

### **Table 9-39. ADCVBUS/PSYS Register (I2C address = 27h) Field Descriptions**



#### **Table 9-40. ADCVBUS/PSYS Register (I2C address = 26h) Field Descriptions**



## **9.6.10 ADCIBAT Register (I2C address = 29/28h)**

- ICHG: Full range: 8.128 A, LSB: 64 mA
- IDCHG: Full range: 32.512 A, LSB: 256 mA

## **Figure 9-30. ADCIBAT Register (I2C address = 29/28h)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

## **Table 9-41. ADCIBAT Register (I2C address = 29h) Field Descriptions**



## **Table 9-42. ADCIBAT Register (I2C address = 28h) Field Descriptions**



## **9.6.11 ADCIINCMPIN Register (I2C address = 2B/2Ah)**

- IIN: Full range: 12.75 A, LSB: 50 mA. For 10mΩ sense resistor, IIN full range =  $6.4A$
- CMPIN: Full range: 3.06 V, LSB: 12 mV

## **Figure 9-31. ADCIINCMPIN Register (I2C address = 2B/2Ah)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

## **Table 9-43. ADCIINCMPIN Register (I2C address = 2Bh) Field Descriptions**



#### **Table 9-44. ADCIINCMPIN Register (I2C address = 2Ah) Field Descriptions**



## **9.6.12 ADCVSYSVBAT Register (I2C address = 2D/2Ch)**

- VSYS: Full range: 2.88 V to 19.2 V, LSB: 64 mV
- VBAT: Full range: 2.88 V to 19.2 V, LSB: 64 mV

### **Figure 9-32. ADCVSYSVBAT Register (I2C address = 2D/2Ch)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

### **Table 9-45. ADCVSYSVBAT Register (I2C address = 2Dh) Field Descriptions**



#### **Table 9-46. ADCVSYSVBAT Register (I2C address = 2Ch) Field Descriptions**



#### **9.6.13 ID Registers**

#### *9.6.13.1 ManufactureID Register (I <sup>2</sup>C address = 2Eh) [reset = 0040h]*

### **Figure 9-33. ManufactureID Register (I2C address = 2Eh) [reset = 0040h]**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 9-47. ManufactureID Register Field Descriptions**



### *9.6.13.2 Device ID (DeviceAddress) Register (I2C address = 2Fh) [reset = 0h]*

#### **Figure 9-34. Device ID (DeviceAddress) Register (I2C address = 2Fh) [reset = 0h]**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 9-48. Device ID (DeviceAddress) Register Field Descriptions**



## <span id="page-69-0"></span>**10 Application and Implementation**

#### **Note**

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

#### **10.1 Application Information**

The BQ2571xEVM-017 evaluation module (EVM) is a complete charger module for evaluating the BQ25713/ BQ25713B. The application curves were taken using the BQ2571xEVM-017. Refer to the [EVM User's Guide](https://www.ti.com/lit/pdf/SLUUBT8) for EVM information.

### **10.2 Typical Application**



**Figure 10-1. Application Diagram**

#### **10.2.1 Design Requirements**



<span id="page-70-0"></span>

(1) Refer to battery specification for settings.

(2) Refer to adapter specification for settings for Input Voltage and Input Current Limit.

#### **10.2.2 Detailed Design Procedure**

The parameters are configurable using the evaluation software. The simplified application circuit (see [Figure](#page-69-0) [10-1,](#page-69-0) as the application diagram) shows the minimum component requirements. Inductor, capacitor, and MOSFET selection are explained in the rest of this section. Refer to the [EVM User's Guide](https://www.ti.com/lit/pdf/SLUUBT8) for the complete application schematic.

#### *10.2.2.1 ACP-ACN Input Filter*

The BQ25713/BQ25713B has average current mode control. The input current sensing through ACP/ACN is critical to recover inductor current ripple. Parasitic inductance on board will generate high frequency ringing on ACP-ACN which overwhelms converter sensed inductor current information, so it is difficult to manage parasitic inductance created based on different PCB layout. Bigger parasitic inductance will generate bigger sense current ringing which will cause the average current control loop to go into oscillation.

For real system board condition, we suggest to use below circuit design to get best result and filter noise induced from different PCB parasitic factor. With time constant of filter from 47 nsec to 200 nsec, the filtering on ringing is effective and in the meantime, the delay of on the sensed signal is small and therefore poses no concern for average current mode control.



**Figure 10-2. ACN-ACP Input Filter**

#### *10.2.2.2 Inductor Selection*

The BQ25713/BQ25713B has two selectable fixed switching frequency. Higher switching frequency allows the use of smaller inductor and capacitor values. Inductor saturation current should be higher than the charging current ( $I_{CHG}$ ) plus half the ripple current ( $I_{RIPPLE}$ ):

$$
I_{\text{SAT}} \geq I_{\text{CHG}} + (1/2) I_{\text{RIPPLE}} \tag{3}
$$

The inductor ripple current in buck operation depends on input voltage (V<sub>IN</sub>), duty cycle (D<sub>BUCK</sub> = V<sub>OUT</sub>/V<sub>IN</sub>), switching frequency  $(f_S)$  and inductance  $(L)$ :

$$
I_{RIPPLE_BUCK} = \frac{V_{IN} \times D \times (1 - D)}{f_S \times L}
$$
 (4)

During boost operation, the duty cycle is:

$$
D_{\text{BOOST}} = 1 - (V_{\text{IN}}/V_{\text{BAT}})
$$

and the ripple current is:

 $I_{RIPPLE\_BOOST}$  = (VIN  $\times$  D<sub>BOOST</sub>) / (f<sub>S</sub>  $\times$  L)

The maximum inductor ripple current happens with  $D = 0.5$  or close to 0.5. For example, the battery charging voltage range is from 9 V to 12.6 V for 3-cell battery pack. For 20-V adapter voltage, 10-V battery voltage gives the maximum inductor ripple current. Another example is 4-cell battery, the battery voltage range is from 12 V to 16.8 V, and 12-V battery voltage gives the maximum inductor ripple current.

Usually inductor ripple is designed in the range of  $(20 - 40%)$  maximum charging current as a trade-off between inductor size and efficiency for a practical design.

#### *10.2.2.3 Input Capacitor*

Input capacitor should have enough ripple current rating to absorb input switching ripple current. The worst case RMS ripple current is half of the charging current (plus system current there is any system load) when duty cycle is 0.5 in buck mode. If the converter does not operate at 50% duty cycle, then the worst case capacitor RMS current occurs where the duty cycle is closest to 50% and can be estimated by Equation 5:

$$
I_{\text{CIN}} = I_{\text{CHG}} \times \sqrt{D \times (1 - D)}
$$
 (5)

Low ESR ceramic capacitor such as X7R or X5R is preferred for input decoupling capacitor and should be placed in front of  $R_{AC}$  current sensing and as close as possible to the power stage half bridge MOSFETs. Capacitance after  $R_{AC}$  before power stage half bridge should be limited to 10 nF + 1 nF referring to [Figure 10-2.](#page-70-0) Because too large capacitance after  $R_{AC}$  could filter out  $R_{AC}$  current sensing ripple information. Voltage rating of the capacitor must be higher than normal input voltage level, 25-V rating or higher capacitor is preferred for 19-V to 20-V input voltage. The minimum input effective capacitance recommendation is shown in Table 10-1.

Ceramic capacitors (MLCC) show a dc-bias effect. This effect reduces the effective capacitance when a dc-bias voltage is applied across a ceramic capacitor, as on the input capacitor of a charger. The effect may lead to a significant capacitance drop, especially for high input voltages and small capacitor packages. See the manufacturer's datasheet about the derating performance with a dc bias voltage applied. It may be necessary to choose a higher voltage rating or nominal capacitance value in order to get the required effective capacitance value at the operating point. Considering the 25 V 0603 package MLCC capacitance derating under 19-V to 20- V input voltage, the recommended practical capacitors configuration can also be found in Table 10-1. Tantalum capacitors (POSCAP) can avoid dc-bias effect and temperature variation effect which is recommended for 90 W to 130 W higher power application.



#### **Table 10-1. Minimum Input Capacitance Requirement**

### *10.2.2.4 Output Capacitor*

Output capacitor also should have enough ripple current rating to absorb output switching ripple current. To get good loop stability, the resonant frequency of the output inductor and output capacitor should be designed between 10 kHz and 20 kHz. The preferred ceramic capacitor is 25-V X7R or X5R for output capacitor. Minimum 7 pcs of 10-μF 0603 package capacitor is suggested to be placed as close as possible to Q3&Q4 half bridge (between Q4 drain and Q3 source terminal). Total minimum output effective capacitance along VSYS distribution line is 50 μF refers to [Table 10-2](#page-72-0). Recommend to place minimum 20-μF MLCC capacitors after the charge current sense resistor for best stability.

Ceramic capacitors show a dc-bias effect. This effect reduces the effective capacitance when a dc-bias voltage is applied across a ceramic capacitor, as on the output capacitor of a charger. The effect may lead to a significant capacitance drop, especially for high output voltages and small capacitor packages. See the manufacturer's data sheet about the derating performance with a dc bias voltage applied. It may be necessary to choose a higher voltage rating or nominal capacitance value in order to get the required capacitance value at the
operating point. Considering the 25-V 0603 package MLCC capacitance derating under 21-V to 23-V output voltage, the recommended practical capacitors configuration at VSYS output terminal can also be found in Table 10-2. Tantalum capacitors (POSCAP) can avoid dc-bias effect and temperature variation effect which are recommended to be used along VSYS output distribution line to meet total minimum effective output capacitance requirement.





#### *10.2.2.5 Power MOSFETs Selection*

Four external N-channel MOSFETs are used for a synchronous switching battery charger. The gate drivers are internally integrated into the IC with 6 V of gate drive voltage. 30 V or higher voltage rating MOSFETs are preferred for 19 V - 20 V input voltage.

Figure-of-merit (FOM) is usually used for selecting proper MOSFET based on a tradeoff between the conduction loss and switching loss. For the top side MOSFET, FOM is defined as the product of a MOSFET's on-resistance,  $R_{DS(ON)}$ , and the gate-to-drain charge,  $Q_{GD}$ . For the bottom side MOSFET, FOM is defined as the product of the MOSFET's on-resistance,  $R_{DS(ON)}$ , and the total gate charge,  $Q_G$ .

$$
FOM_{top} = R_{DS(on)} \times Q_{GD}; FOM_{bottom} = R_{DS(on)} \times Q_G
$$
\n
$$
(6)
$$

The lower the FOM value, the lower the total power loss. Usually lower  $R_{DS(ON)}$  has higher cost with the same package size.

The top-side MOSFET loss includes conduction loss and switching loss. It is a function of duty cycle (D=V<sub>OUT</sub>/  $V_{\text{IN}}$ ), charging current ( $I_{\text{CHG}}$ ), MOSFET's on-resistance ( $R_{\text{DS}(\text{ON})}$ ), input voltage ( $V_{\text{IN}}$ ), switching frequency (f<sub>S</sub>), turn on time  $(t_{on})$  and turn off time  $(t_{off})$ :

$$
P_{top} = D \times I_{CHG}^2 \times R_{DS(on)} + \frac{1}{2} \times V_{IN} \times I_{CHG} \times (t_{on} + t_{off}) \times f_s
$$
\n(7)

The first item represents the conduction loss. Usually MOSFET  $R_{DS(ON)}$  increases by 50% with 100°C junction temperature rise. The second term represents the switching loss. The MOSFET turn-on and turn-off times are given by:

$$
t_{on} = \frac{Q_{SW}}{I_{on}}, \quad t_{off} = \frac{Q_{SW}}{I_{off}}
$$
 (8)

where  $Q_{sw}$  is the switching charge,  $I_{on}$  is the turn-on gate driving current and  $I_{off}$  is the turn-off gate driving current. If the switching charge is not given in MOSFET datasheet, it can be estimated by gate-to-drain charge  $(Q_{GD})$  and gate-to-source charge  $(Q_{GS})$ :

$$
Q_{SW} = Q_{GD} + \frac{1}{2} \times Q_{GS}
$$
\n(9)

Gate driving current can be estimated by REGN voltage (V<sub>REGN</sub>), MOSFET plateau voltage (V<sub>olt</sub>), total turn-on gate resistance  $(R_{on})$  and turn-off gate resistance  $(R_{off})$  of the gate driver:

$$
I_{on} = \frac{V_{REGN} - V_{plt}}{R_{on}}, I_{off} = \frac{V_{plt}}{R_{off}}
$$
(10)

The conduction loss of the bottom-side MOSFET is calculated with the following equation when it operates in synchronous continuous conduction mode:

$$
P_{bottom} = (1 - D) \times I_{CHG}^2 \times R_{DS(on)}
$$
 (11)

When charger operates in non-synchronous mode, the bottom-side MOSFET is off. As a result all the freewheeling current goes through the body-diode of the bottom-side MOSFET. The body diode power loss depends on its forward voltage drop ( $V_F$ ), non-synchronous mode charging current ( $I_{NONSYNC}$ ), and duty cycle (D).

$$
P_D = V_F x I_{NONSYNC} x (1 - D)
$$
 (12)

The maximum charging current in non-synchronous mode can be up to 0.25 A for a 10-m $\Omega$  charging current sensing resistor or 0.5 A if battery voltage is below 2.5 V. The minimum duty cycle happens at lowest battery voltage. Choose the bottom-side MOSFET with either an internal Schottky or body diode capable of carrying the maximum non-synchronous mode charging current.

#### **10.2.3 Application Curves**





**[BQ25713,](https://www.ti.com/product/BQ25713) [BQ25713B](https://www.ti.com/product/BQ25713B)** SLUSD83B – JUNE 2018 – REVISED FEBRUARY 2021





## **11 Power Supply Recommendations**

The valid adapter range is from 3.5 V ( $V_{VBUS\_CONVEN}$  ) to 24 V (ACOV) with at least 500-mA current rating. When CHRG\_OK goes HIGH, the system is powered from adapter through the charger. When adapter is removed, the system is connected to battery through BATFET. Typically the battery depletion threshold should be greater than the minimum system voltage so that the battery capacity can be fully utilized for maximum battery life.

## **12 Layout 12.1 Layout Guidelines**

Proper layout of the components to minimize high frequency current path loop (see [Section 12.2\)](#page-79-0) is important to prevent electrical and magnetic field radiation and high frequency resonant problems. Here is a PCB layout priority list for proper layout.

<b>RULES</b>	<b>COMPONENTS</b>	<b>FUNCTION</b>	<b>IMPACT</b>	<b>GUIDELINES</b>
$\mathbf{1}$		PCB layer stack up	Thermal, efficiency, signal integrity	Multi- layer PCB is suggested. Allocate at least one ground layer. The BQ257XXEVM uses a 4-layer PCB (top layer, ground layer, signal layer and bottom layer).
2	CBUS, RAC, Q1, Q2	Input loop	High frequency noise, ripple	VBUS capacitors, RAC, Q1 and Q2 form a small loop 1. It is best to put them on the same side. Connect them with large copper to reduce the parasitic resistance. Move part of CBUS to the other side of PCB for high density design. After RAC before Q1 and Q2 power stage recommend to put 10 nF + 1 nF (0402 package) decoupling capacitors as close as possible to IC to decoupling switching loop high frequency noise.
3	R <sub>AC</sub> , Q1, L1, Q4	Current path	Efficiency	The current path from VBUS to VSYS, through R <sub>AC</sub> , Q1, L1, Q4, has low impedance. Pay attention to via resistance if they are not on the same side. The number of vias can be estimated as 1 to 2A/via for a 10-mil via with 1 oz. copper thickness.
4	CSYS, Q3, Q4	Output loop	High frequency noise, ripple	VSYS capacitors, Q3 and Q4 form a small loop 2. It is best to put them on the same side. Connect them with large copper to reduce the parasitic resistance. Move part of CSYS to the other side of PCB for high density design.
5	QBAT, R <sub>SR</sub>	Current path	Efficiency, battery voltage detection	Place QBAT and $R_{SR}$ near the battery terminal. The current path from VBAT to VSYS, through R <sub>SR</sub> and QBAT, has low impedance. Pay attention to via resistance if they are not on the same side. The device detects the battery voltage through SRN near battery terminal.
6	Q1, Q2, L1, Q3, Q4	Power stage	Thermal, efficiency	Place Q1, Q2, L1, Q3 and Q4 next to each other. Allow enough copper area for thermal dissipation. The copper area is suggested to be 2x to 4x of the pad size. Multiple thermal vias can be used to connect more copper layers together and dissipate more heat.
$\overline{7}$	$R_{AC}$ , $R_{SR}$	Current sense	Regulation accuracy	Use Kelvin-sensing technique for $R_{AC}$ and $R_{SR}$ current sense resistors. Connect the current sense traces to the center of the pads, and run current sense traces as differential pairs.
8	Small capacitors	IC bypass caps	Noise, jittering, ripple	Place VBUS cap, VCC cap, REGN caps near IC.
9	<b>BST</b> capacitors	HS gate drive	High frequency noise, ripple	Place HS MOSFET boost strap circuit capacitor close to IC and on the same side of PCB board. Capacitors SW1/2 nodes are recommended to use wide copper polygon to connect to power stage and capacitors BST1/2 node are recommended to use at least 8 mil trace to connected to IC BST1/2 pins.
10		Ground partition	Measurement accuracy, regulation accuracy, jitters, ripple	Separate analog ground(AGND) and power grounds(PGND) is preferred. PGND should be used for all power stage related ground net. AGND should be used for all sensing, compensation and control network ground for example ACP/ACN/COMP1/ COMP2/CMPIN/CMPOUT/IADPT/IBAT/PSYS. Connect all analog grounds to a dedicated low-impedance copper plane, which is tied to the power ground underneath the IC exposed pad. If possible, use dedicated COMP1, COMP2 AGND traces. Connect analog ground and power ground together using power pad as the single ground connection point.

**Table 12-1. PCB Layout Guidelines**

## <span id="page-79-0"></span>**12.2 Layout Example**

#### **12.2.1 Layout Example Reference Top View**

Based on the above layout guidelines, the buck-boost charger layout example top view is shown below including all the key power components.



**Figure 12-1. Buck-Boost Charger Layout Reference Example Top View**

#### **12.2.2 Inner Layer Layout and Routing Example**

For both input sensing resistor and charging current sensing resistor, differential sensing and routing method are suggested and highlighted in below figure. Use wide trace for gate drive traces, minimum 15 mil trace width. Connect all analog grounds to a dedicated low-impedance copper plane, which is tied to the power ground underneath the IC exposed pad. Suggest using dedicated COMP1, COMP2 analog ground traces shown in below figure.



**Figure 12-2. Buck-Boost Charger Gate Drive/Current Sensing/AGND Signal Layer Routing Example**

## **13 Device and Documentation Support**

#### **13.1 Device Support**

#### **13.1.1 Third-Party Products Disclaimer**

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## **13.2 Documentation Support**

#### **13.2.1 Related Documentation**

For related documentation see the following:

- *[Semiconductor and IC Package Thermal Metrics Application Report](https://www.ti.com/lit/pdf/SPRA953)*
- *[BQ2571x Evaluation Module User's Guide](https://www.ti.com/lit/pdf/SLUUBT8)*
- *[QFN/SON PCB Attachment Application Report](https://www.ti.com/lit/pdf/SLUA271)*

#### **13.3 Receiving Notification of Documentation Updates**

To receive notification of documentation updates, navigate to the device product folder on [ti.com.](https://www.ti.com) Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### **13.4 Support Resources**

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#### **13.6 Electrostatic Discharge Caution**



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### **13.7 Glossary**

**[TI Glossary](https://www.ti.com/lit/pdf/SLYZ022)** This glossary lists and explains terms, acronyms, and definitions.

## **14 Mechanical, Packaging, and Orderable Information**

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

## **PACKAGING INFORMATION**



**(1)** The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

**(3)** MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

**(4)** There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

**(6)** Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

1-Jan-2021

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3-Jun-2022

## **TAPE AND REEL INFORMATION**





#### **QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**





# **PACKAGE MATERIALS INFORMATION**

3-Jun-2022





# MECHANICAL DATA



C. QFN (Quad Flatpack No-Lead) Package configuration.

D. The package thermal pad must be soldered to the board for thermal and mechanical performance.

E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.

## RSN (S-PWQFN-N32)

## PLASTIC QUAD FLATPACK NO-LEAD

#### THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. [SLUA271.](http://www.ti.com/lit/slua271) This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.





RSN (S-PWQFN-N32) PLASTIC QUAD FLATPACK NO-LEAD



- B. This drawing is subject to change without notice.
- Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. [SLUA](http://www.ti.com/lit/slua271)271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding comers will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.

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